

CPW3-1700S025-Silicon Carbide Schottky Diode Chip

Z - Rec^{TM} Rectifier		V _{RRM}	= 1700 V
		I _{F(AVC}	_{s)} = 25 A
Features	Chip Outline	\mathbf{Q}_{c}	= 170 nC

- 1700-Volt Schottky Rectifier ٠
- Zero Reverse Recovery ٠
- Zero Forward Recovery •
- High-Frequency Operation •
- Temperature-Independent Switching Behavior •
- Extremely Fast Switching •
- Positive Temperature Coefficient on V_F •



Part Number	Anode	Cathode	Package	Marking
CPW3-1700S025B	AI	Ni/Ag	Sawn on Foil	Wafer # on Foil

Maximum Ratings

Symbol	Parameter	Value	Unit	Test Conditions	Note
V _{RRM}	Repetitive Peak Reverse Voltage	1700	V		
V _{RSM}	Surge Peak Reverse Voltage	1700	V		
V _{DC}	DC Blocking Voltage	1700	V		
$I_{\rm F(AVG)}$	Average Forward Current	25	А	T _j =175°C	
I _{frm}	Repetitive Peak Forward Surge Current	82 43	А	$T_c=25$ °C, $t_p=10$ ms, Half Sine Wave, D=1 $T_c=110$ °C, $t_p=10$ ms, Half Sine Wave, D=1	1
I _{fsm}	Non-Repetitive Peak Forward Surge Current	117 84	A	$T_c=25$ °C, $t_p=10$ ms, Half Sine Wave, D=1 $T_c=110$ °C, $t_p=10$ ms, Half Sine Wave, D=1	1
T _j , T _{stg}	Operating Junction and Storage Temperature	-55 to +175	°C		

Electrical Characteristics

Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
V _F	Forward Voltage	1.8 3.2	2 4	V	$I_F = 25 \text{ A } T_J = 25^{\circ}\text{C}$ $I_F = 25 \text{ A } T_J = 175^{\circ}\text{C}$	
I _R	Reverse Current	20 100	100 400	μA	$V_{R} = 1700 V T_{J} = 25^{\circ}C$ $V_{R} = 1700 V T_{J} = 175^{\circ}C$	
Q _c	Total Capacitive Charge	170	270	nC	V _R = 1700 V, I _F = 25 A di/dt = 400 A/µs T _J = 25°C	
с	Total Capacitance	2250 200 140		pF		

Note:

1. Assumes θ_{J-C} Thermal Resistance of 0.63°C/W or less.

Subject to change without notice. www.cree.com/power



Typical Performance

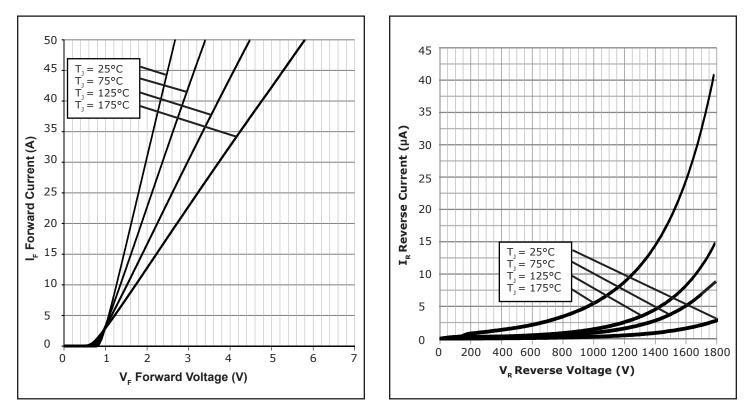
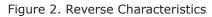


Figure 1. Forward Characteristics



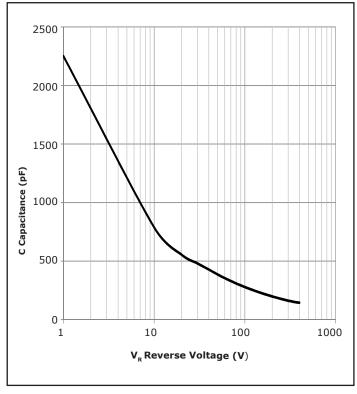


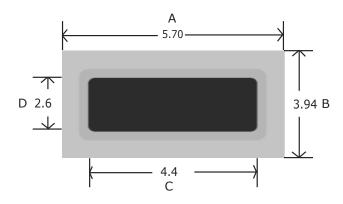
Figure 3. Capacitance vs. Reverse Voltage



Mechanical Parameters

Parameter	Тур.	Unit
Die Size	5.70 X 3.94	mm
Anode Pad Size	5.1 X 3.3	mm
Anode Pad Opening	4.4 X 2.6	mm
Thickness	387 ± 10%	μm
Anode Metalization (Al)	4	μm
Cathode Metalization (Ni/Ag)	1.8	μm

Chip Dimensions



Symbol	Dimension mm inch		
А	5.70	0.224	
В	3.94	0.155	
С	4.4	0.173	
D	2.6	0.102	

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The die-on-tape method of delivering these SiC die may be considered a means of temporary storage only. Due to an increase in adhesion over time die stored for an extended period may affix too strongly to the tape. These die should be stored in a temperature-controlled nitrogen dry box soon after receipt. Cree will further recommend that all die be removed from tape to a waffle pack, to a similar storage medium, or used in production within 2 – 3 weeks of delivery to assure 100% release of all die without issues.

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical equipment, aircraft navigation or communication or control systems, air traffic control systems, or weapons systems.

Cree, Inc. 4600 Silicon Drive Durham, NC 27703 USA Tel: +1.919.313.5300 Fax: +1.919.313.5451 www.cree.com/power

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